

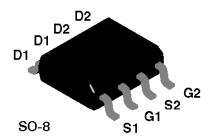
# NDS9957 Dual N-Channel Enhancement Mode Field Effect Transistor

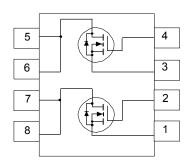
# **General Description**

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulses in the avalanche and commutation modes. These devices are particularly suited for low voltage applications such as DC motor control and DC/DC conversion where fast switching, low in-line power loss, and resistance to transients are needed.

## **Features**

- 2.6A, 60V.  $R_{DS(ON)} = 0.16\Omega$  @  $V_{GS} = 10V$ .
- High density cell design for extremely low R<sub>DS(ON)</sub>.
- High power and current handling capability in a widely used surface mount package.
- Dual MOSFET in surface mount package.





# Absolute Maximum Ratings T<sub>a</sub> = 25°C unless otherwise noted

Symbol	Parameter		NDS9957	Units
V <sub>DSS</sub>	Drain-Source Voltage		60	V
V <sub>GSS</sub>	Gate-Source Voltage		± 20	V
D	Drain Current - Continuous	(Note 1a)	± 2.6	A
	- Pulsed		± 10	
<b>)</b>	Power Dissipation for Dual Operation		2	W
	Power Dissipation for Single Operation	(Note 1a)	1.6	
		(Note 1b)	1	
		(Note 1c)	0.9	
$T_J, T_{STG}$	Operating and Storage Temperature Range		-55 to 150	°C
THERMA	L CHARACTERISTICS	·		·
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	78	°C/W
R <sub>⊕IC</sub>	Thermal Resistance, Junction-to-Case	(Note 1)	40	°C/W

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Symbol	Parameter	Conditions		Min	Тур	Max	Units
OFF CHA	RACTERISTICS			•			
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$		60			V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = 48 \text{ V}, V_{GS} = 0 \text{ V}$				1	μA
I <sub>GSSF</sub>	Gate - Body Leakage, Forward	V <sub>GS</sub> = 20 V, V <sub>DS</sub> = 0 V				100	nA
I <sub>GSSR</sub>	Gate - Body Leakage, Reverse	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
ON CHAR	ACTERISTICS (Note 2)						
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$		1	1.5	3	V
			T <sub>A</sub> = 125°C	0.7	1.1	2.2	
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	$V_{GS} = 10 \text{ V}, I_{D} = 2.6 \text{ A}$	•		0.145	0.16	Ω
			T <sub>A</sub> = 125°C		0.25	0.3	
		$V_{gs} = 4.5 \text{ V}, I_{D} = 2.1 \text{ A}$			0.19	0.25	-
			T <sub>A</sub> = 125°C		0.32	0.5	
I <sub>D(on)</sub>	On-State Drain Current	$V_{GS} = 10 \text{ V}, V_{DS} = 5 \text{ V}$		10			Α
<b>g</b> <sub>FS</sub>	Forward Transconductance	$V_{DS} = 5 \text{ V}, I_{D} = 2.6 \text{ A}$			4		S
DYNAMIC	CHARACTERISTICS						
C <sub>iss</sub>	Input Capacitance	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz			200		pF
C <sub>oss</sub>	Output Capacitance				60		pF
C <sub>rss</sub>	Reverse Transfer Capacitance				20		pF
SWITCHIN	IG CHARACTERISTICS (Note 2)						
t <sub>D(on)</sub>	Tum - On Delay Time	$V_{DD} = 30 \text{ V}, I_{D} = 1 \text{ A},$ $V_{GS} = 10 \text{ V}, R_{GEN} = 6 \Omega$			6	20	ns
t,	Turn - On Rise Time				11	25	ns
$\mathbf{t}_{D(off)}$	Turn - Off Delay Time				17	30	ns
t <sub>r</sub>	Turn - Off Fall Time				4	15	ns
$Q_g$	Total Gate Charge	$V_{DS} = 30 \text{ V},$ $I_D = 2.6 \text{ A}, V_{GS} = 10 \text{ V}$			7.5	12	nC
$Q_{gs}$	Gate-Source Charge				2.8		nC
$Q_{gd}$	Gate-Drain Charge				8.0		nC

Electrical Characteristics (T <sub>A</sub> = 25°C unless otherwise noted)							
Symbol	Parameter Conditions		Min	Тур	Max	Units	
DRAIN-SOURCE DIODE CHARACTERISTICS AND MAXIMUM RATINGS							
Is	Maximum Continuos Drain-Source Diode Forward Current				1.7	Α	
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 2.6 A (Note 2)		0.9	1.2	V	

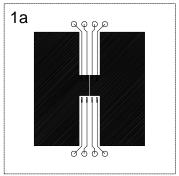
#### Notes:

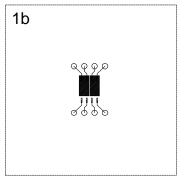
1. R<sub>BA</sub> is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R<sub>BA</sub> is guaranteed by design while R<sub>BA</sub> is determined by the user's board design.

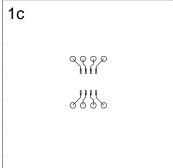
$$P_D(t) = \frac{T_J - T_A}{R_{\theta J} \, \hat{A}^{(t)}} = \frac{T_J - T_A}{R_{\theta J} \, \hat{c}^t R_{\theta C} \hat{A}^{(t)}} = I_D^2(t) \times R_{DS(ON) \cdot \P T_J}$$

Typical  $R_{\text{BJA}}$  for single device operation using the board layouts shown below on 4.5"x5" FR-4 PCB in a still air environment:

- a. 78°C/W when mounted on a 0.5 in² pad of 2oz cpper.
- b. 125°C/W when mounted on a 0.02 in² pad of 2oz cpper.
- c. 135°C/W when mounted on a 0.003 in<sup>2</sup> pad of 2oz cpper.







Scale 1:1 on letter size paper

2. Pulse Test: Pulse Width  $\leq$  300 $\mu$ s, Duty Cycle  $\leq$  2.0%.

# **Typical Electrical Characteristics**

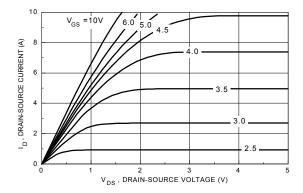


Figure 1. On-Region Characteristics.

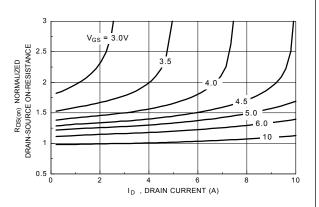


Figure 2. On-Resistance Variation with Gate Voltage and Drain Current.

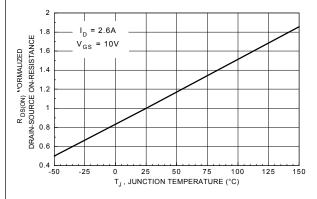


Figure 3. On-Resistance Variation with Temperature.

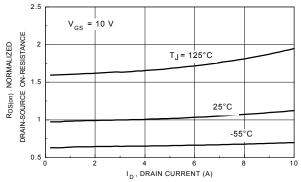


Figure 4. On-Resistance Variation with Drain Current and Temperature.

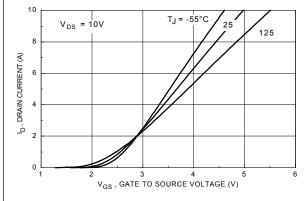


Figure 5. Transfer Characteristics.

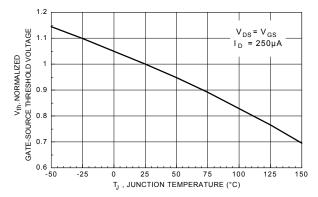


Figure 6. Gate Threshold Variation with Temperature.

NDS9957.SAM

# **Typical Electrical Characteristics** (continued)

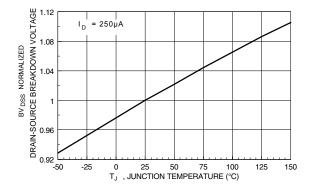


Figure 7. Breakdown Voltage Variation with Temperature.

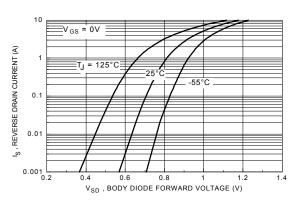


Figure 8. Body Diode Forward Voltage Variation with Current and Temperature.

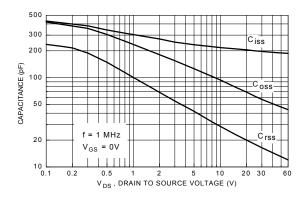


Figure 9. Capacitance Characteristics.

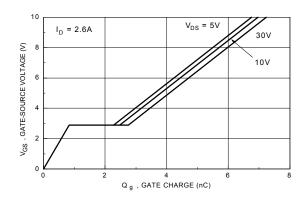


Figure 10. Gate Charge Characteristics.

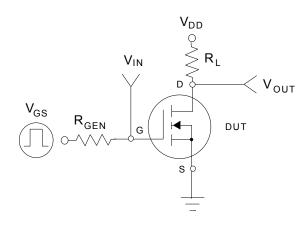


Figure 11. Switching Test Circuit

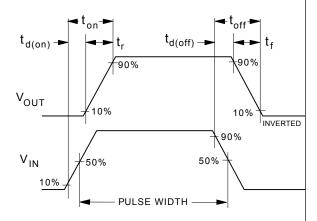
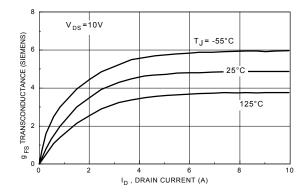


Figure 12. Switching Waveforms

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# **Typical Electrical Characteristics** (continued)



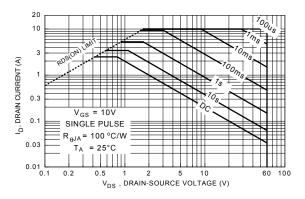


Figure 13. Transconductance Variation with Drain Current and Temperature.

Figure 14. Maximum Safe Operating Area.

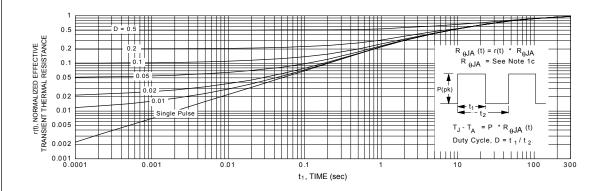
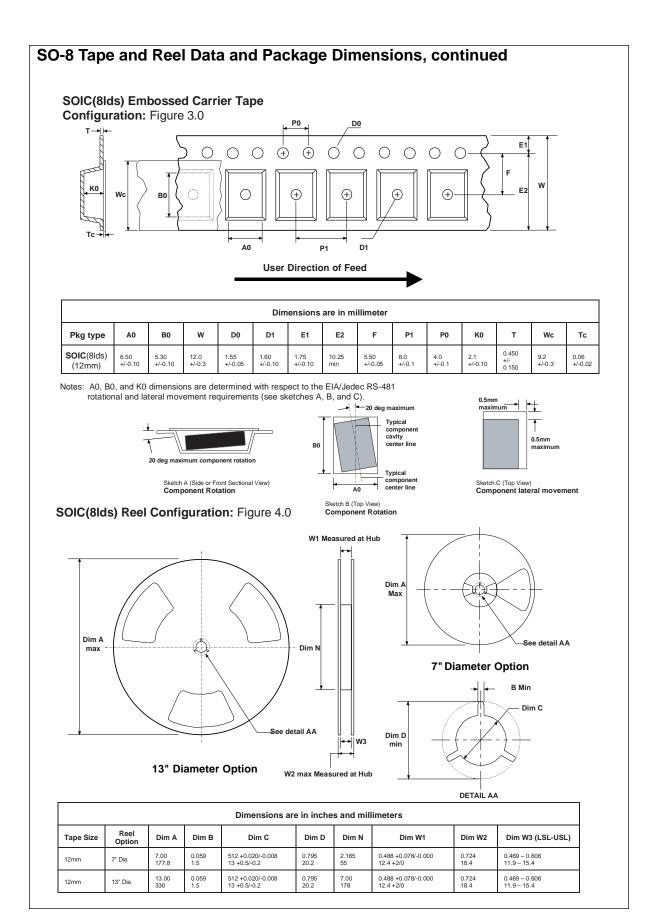


Figure 15. Transient Thermal Response Curve.

Note: Thermal characterization performed using the conditions described in note 1c. Transient thermal response will change depending on the circuit board design.

#### SO-8 Tape and Reel Data and Package Dimensions FAIRCHILD SEMICONDUCTOR IM SOIC(8lds) Packaging Configuration: Figure 1.0 FAIRCH**I**LD **Packaging Description:** Packaging Description: SOIC-8 parts are shipped in tape. The carrier tape is made from a dissipative (carbon filled) polycarbonate resin. The cover tape is a multilayer film (Heat Activated Adhesive in nature) primarily composed of polyester film, adhesive layer, sealant, and amit-static sprayed agent. These reeled parts in standard option are shipped with 2,500 units per 13° or 300cm diameter reel. The reels are dark blue in color and is made of polystyrene plastic (antistatic coated). Other option comes in 500 units per 7° or 177cm diameter reel. This and some other options are further described in the Packaging Information table. Antistatic Cover Tape ESD Label These full reles are individually barcode labeled and placed inside a standard intermediate box (illustrated in figure 1.0) made of recyclable corrugated brown paper. One box contains two reels maximum. And these boxes are placed inside a barcode labeled shipping box which comes in different sizes depending on the number of parts shipped. Static Dissipative Embossed Carrier Tape 63TNR Label Customized Label SOIC (8lds) Packaging Information Packaging Option Standard o flow code) L86Z D84Z **SOIC-8 Unit Orientation** Rail/Tube TNR Packaging type TNR TNR Qty per Reel/Tube/Bag 2.500 4.000 500 Reel Size 13" Dia 13" Dia 7" Dia Box Dimension (mm) 343y64y343 530x130x83 343y64y343 184v187v47 Max qty per Box 5,000 30,000 8,000 1,000 Weight per unit (gm) 0.0774 0.0774 0.0774 0.0774 Weight per Reel (kg) 0.6060 0.9696 0.1182 Note/Comments 343mm x 342mm x 64mm Standard Intermediate box ESD Label F63TNR Label sample F63TNI F63TN Label LOT: CBVK741B019 QTY: 2500 D/C1: D9842 D/C2: SOIC(8lds) Tape Leader and Trailer Configuration: Figure 2.0 0 0 0 0 0 0 0 $\bigcirc$ 0 Components Cover Tape Trailer Tape Leader Tape 1680mm minimum or 640mm minimum or 80 empty pockets 210 empty pockets



# SO-8 Tape and Reel Data and Package Dimensions, continued SOIC-8 (FS PKG Code S1) 1:1 Scale 1:1 on letter size paper Dimensions shown below are in: inches [millimeters] Part Weight per unit (gram): 0.0774 LEAD NO. IDENTIFICATION 0.0200 [0.51] 0.2260 [5.74] 0.0390 [0.99] 0.0500 [1.27] - 0.0500 [1.27] 0.010[0.25](M) [0.25] A CS B LAND PATTERN RECOMMENDATION GAGE PLANE 0.004[0.10] 3 0.0140 [0.36] ALL LEAD TIPS 1.27 TYP. ALL LEADS NOTES: UNLESS OTHERWISE SPECIFIED 1. STANDARD LEAD FINISH: 200 MICROINCHES / 5.08 MICRONS MINIMUM LEAD / TIN (SOLDER) ON COPPER. SO 0.150 WIDE 8 LEADS THESE DIMENSIONS DO NOT INCLUDE MOLD FLASH MAXIMUM LEAD 0.024 [0.609]

September 1998, Rev. A

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Rev. B